



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOD294A/AOI294A**  
100V N-Channel AlphaSGT™

### General Description

- Trench Power AlphaSGT™ technology
- Low  $R_{DS(ON)}$
- Logic Level Driving
- Excellent  $Q_G \times R_{DS(ON)}$  Product (FOM)
- Pb-Free lead Plating, RoHS and Halogen-Free Compliant

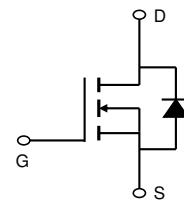
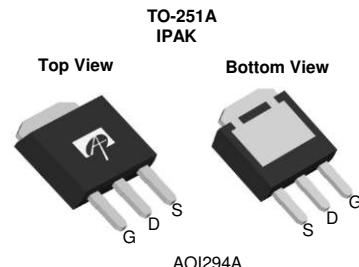
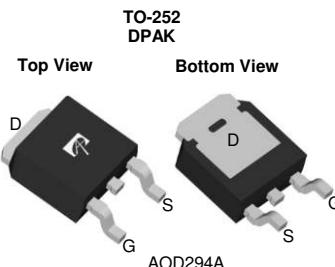
### Applications

- High Frequency Switching and Synchronous Rectification

### Product Summary

$V_{DS}$	100V
$I_D$ (at $V_{GS}=10V$ )	55A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 12mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 15.5mΩ

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOD294A	TO-252	Tape & Reel	2500
AOI294A	TO-251A	Tube	4000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	55	A
$T_C=100^\circ C$		35	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	138	A
Continuous Drain Current	$I_{DSM}$	16	A
$T_A=70^\circ C$		13	
Avalanche Current <sup>C</sup>	$I_{AS}$	25	A
Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AS}$	31	mJ
$V_{DS}$ Spike <sup>I</sup>	$V_{SPIKE}$	120	V
Power Dissipation <sup>B</sup>	$P_D$	73	W
$T_C=100^\circ C$		30	
Power Dissipation <sup>A</sup>	$P_{DSM}$	6.2	W
$T_A=70^\circ C$		4.0	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.35	1.7	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	100			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.5	2.0	2.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$	10	12		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$	18	22		
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$	67			S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	0.71	1		V
$I_S$	Maximum Body-Diode Continuous Current				55	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=50\text{V}, f=1\text{MHz}$		2305		pF
$C_{oss}$	Output Capacitance			180		pF
$C_{rss}$	Reverse Transfer Capacitance			11.5		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	0.2	0.5	1.0	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, I_D=20\text{A}$		32.5	50	nC
$Q_g(4.5\text{V})$	Total Gate Charge			15.5	25	nC
$Q_{gs}$	Gate Source Charge			6.5		nC
$Q_{gd}$	Gate Drain Charge			5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, R_L=2.5\Omega, R_{\text{GEN}}=3\Omega$		7		ns
$t_r$	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			27		ns
$t_f$	Turn-Off Fall Time			4		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		29.5		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, di/dt=500\text{A}/\mu\text{s}$		160		nC

A. The value of  $R_{JJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{DSM}$  is based on  $R_{JJA} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{JJA}$  is the sum of the thermal impedance from junction to case  $R_{JJC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

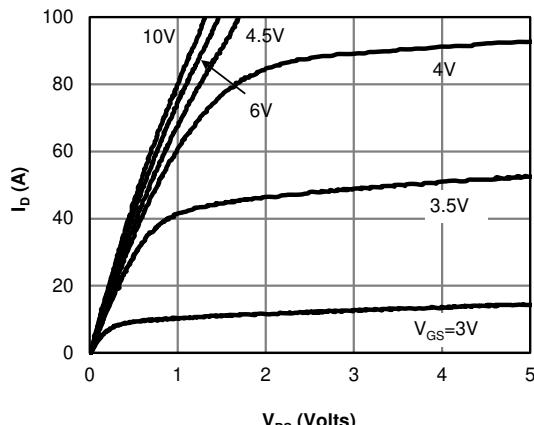
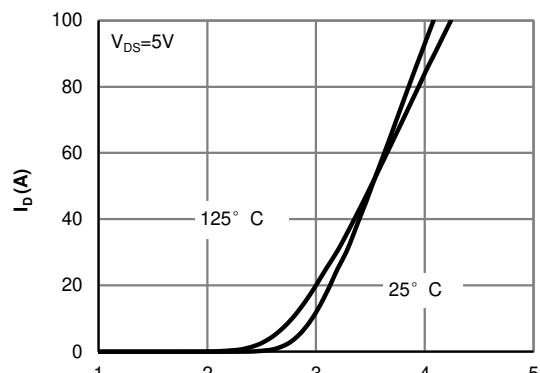
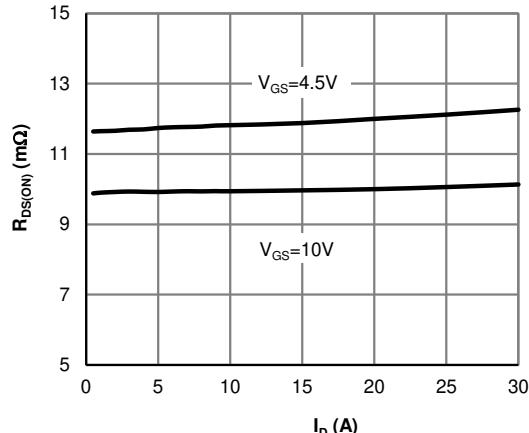
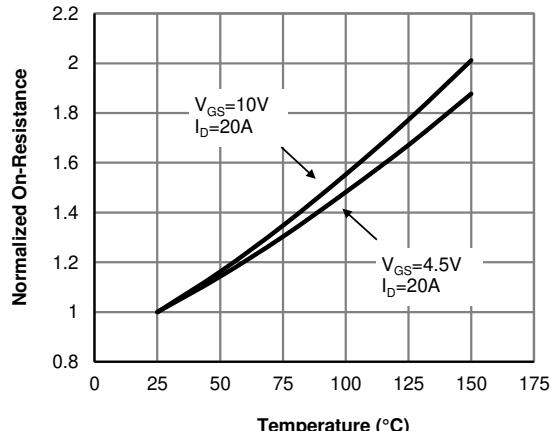
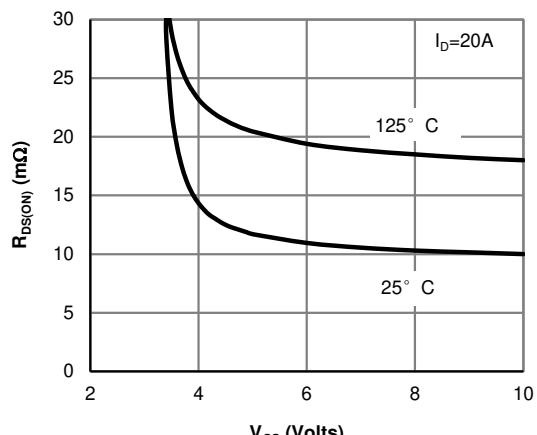
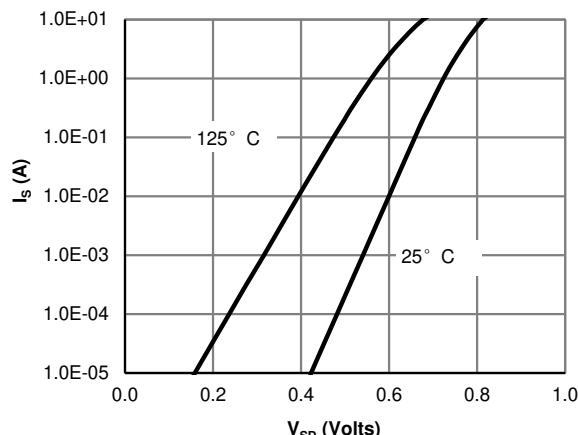
H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

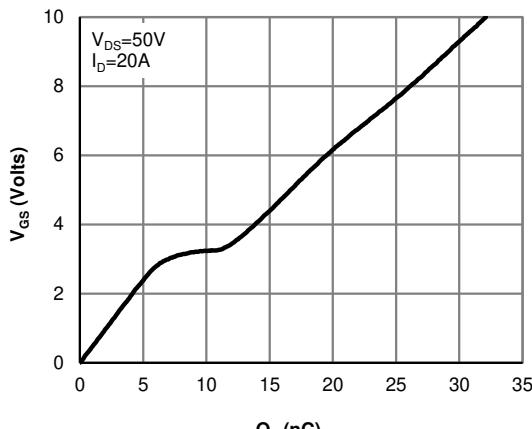
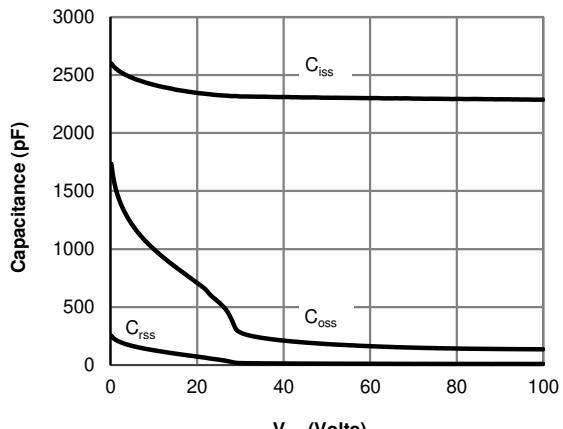
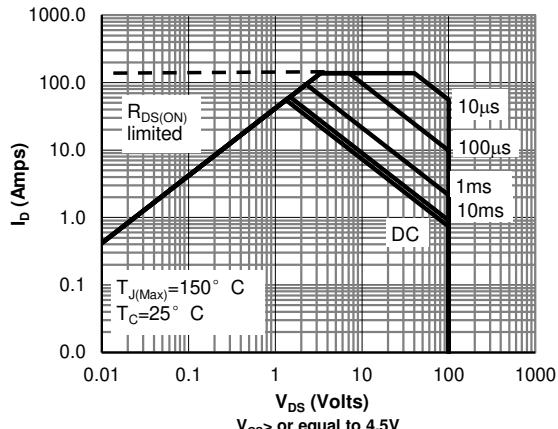
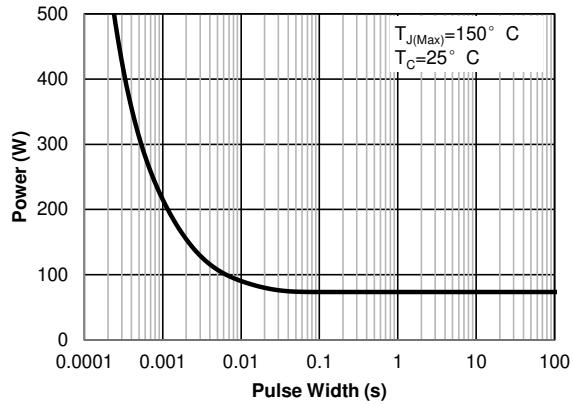
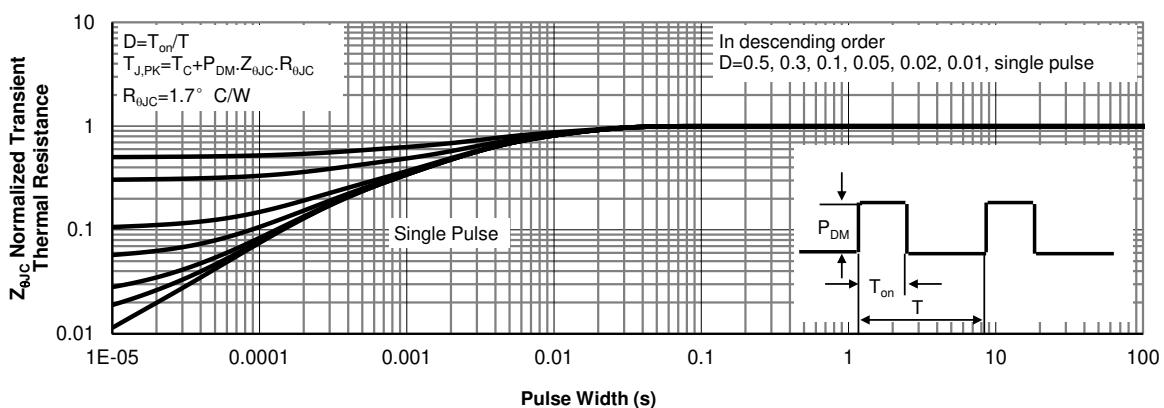
I.  $L=100\mu\text{H}$ ,  $F_{sw}=1\text{Hz}$ ,  $T_J \leq 150^\circ\text{C}$  by repetitive UIS.

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

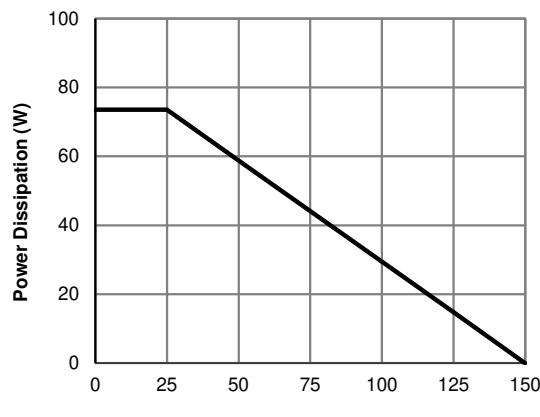
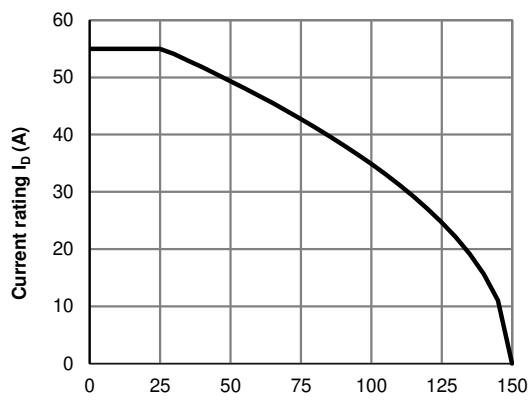
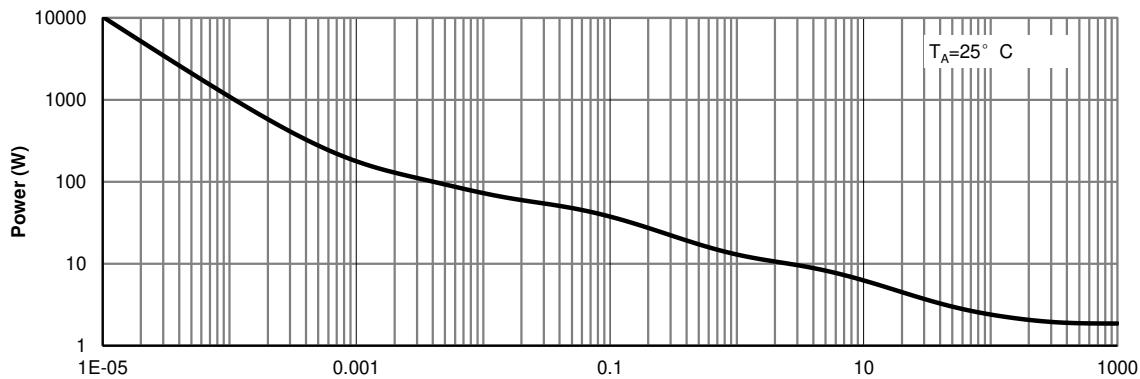
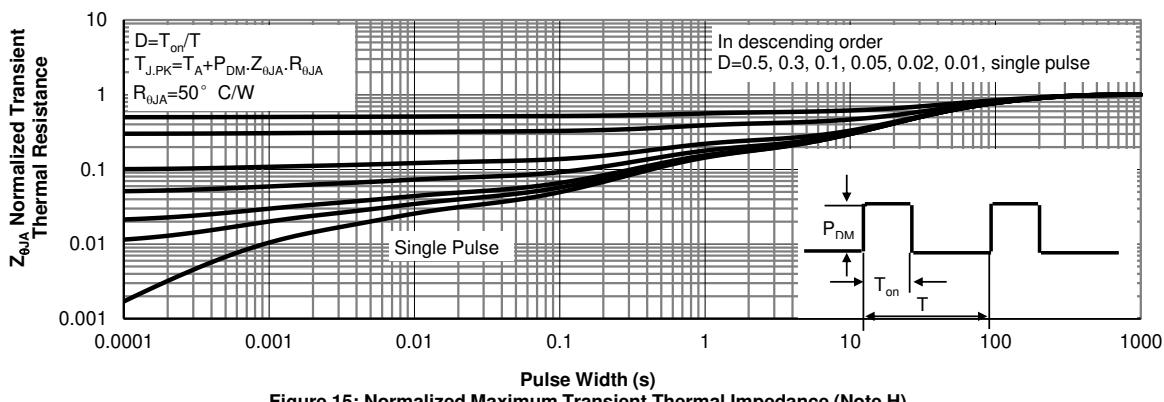
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 12: Power De-rating (Note F)**

**Figure 13: Current De-rating (Note F)**

**Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)**

**Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)**

Figure A: Gate Charge Test Circuit & Waveforms

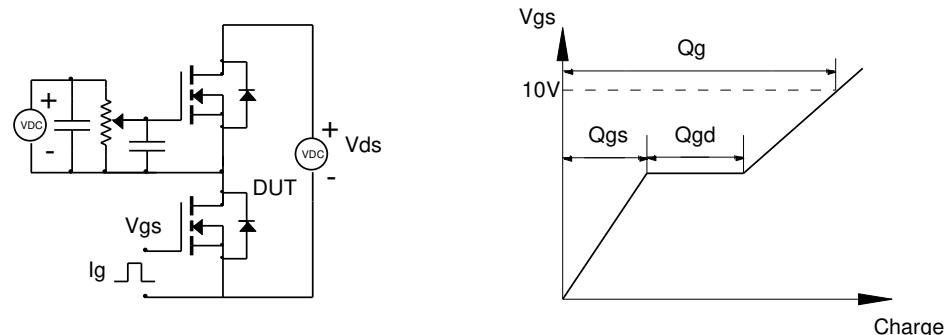


Figure B: Resistive Switching Test Circuit & Waveforms

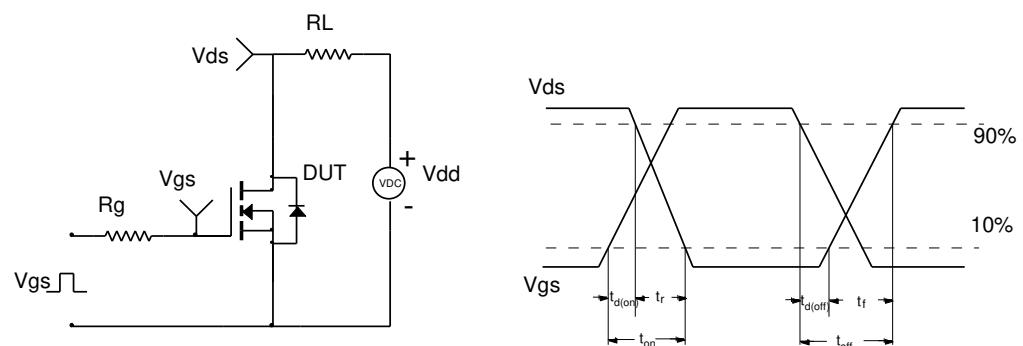


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

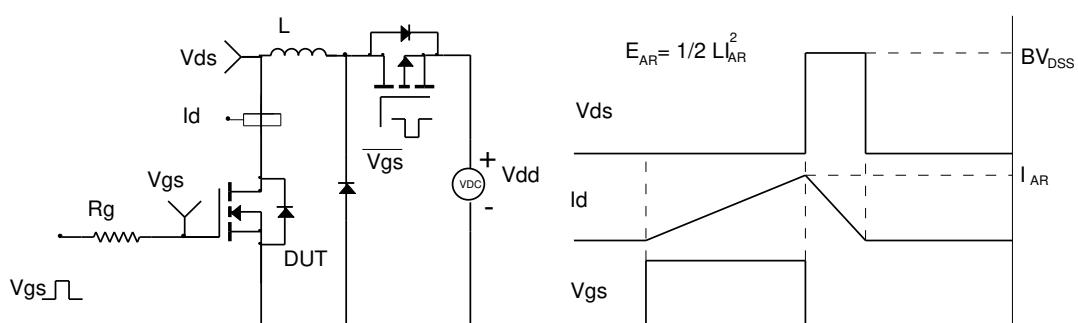


Figure D: Diode Recovery Test Circuit & Waveforms

